

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): KOMURA et al.	Atty. Dkt.: 1-50
Serial No.: Unknown	Group Art Unit:
Filed: Concurrently herewith	Examiner:
Title: METHOD FOR MEASURING THICKNESS OF OXIDE FILM	
Assistant Commissioner for Patents Washington, D.C. 20231	Date: July 13, 2000



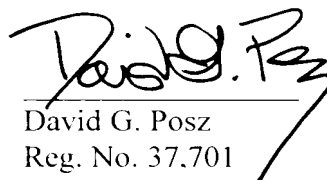
INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §1.56, the references listed on the attached Form PTO-1449 are being submitted for consideration by the Examiner. The references are submitted without any admission that such references constitute statutory prior art, or without any admission that the references contain subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed references have been considered and made of record.

Respectfully submitted,


David G. Posz
Reg. No. 37,701

Law Office of David G. Posz
601 Pennsylvania Avenue, N.W.
Suite 900, South Building
Washington, D.C. 20004
(202) 220-3105 (phone)
(202) 220-3106 (fax)